

FQP10N20L

200V LOGIC N-Channel MOSFET

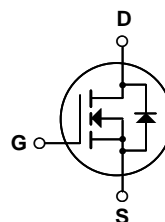
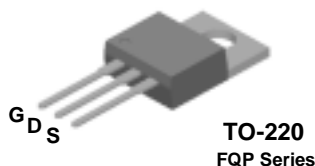
General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, and motor control.

Features

- 10A, 200V, $R_{DS(on)} = 0.36\Omega @ V_{GS} = 10V$
- Low gate charge (typical 13 nC)
- Low Crss (typical 14 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Low level gate drive requirement allowing direct operation from logic drivers



Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter	FQP10N20L	Units
V _{DSS}	Drain-Source Voltage	200	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)	10	A
		6.3	A
I _{DM}	Drain Current - Pulsed (Note 1)	40	A
V _{GSS}	Gate-Source Voltage	± 20	V
E _{AS}	Single Pulsed Avalanche Energy (Note 2)	180	mJ
I _{AR}	Avalanche Current (Note 1)	10	A
E _{AR}	Repetitive Avalanche Energy (Note 1)	8.7	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	5.5	V/ns
P _D	Power Dissipation (T _C = 25°C) - Derate above 25°C	87	W
		0.7	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	°C

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
R _{θJC}	Thermal Resistance, Junction-to-Case	--	1.44	°C/W
R _{θCS}	Thermal Resistance, Case-to-Sink	0.5	--	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient	--	62.5	°C/W

Electrical CharacteristicsT_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	200	--	--	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	--	0.18	--	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 200 V, V _{GS} = 0 V	--	--	1	μA
		V _{DS} = 160 V, T _C = 125°C	--	--	10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V	--	--	100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V	--	--	-100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	1.0	--	2.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 5.0 A	--	0.29	0.36	Ω
		V _{GS} = 5 V, I _D = 5.0 A (Note 4)	--	0.3	0.38	
g _{FS}	Forward Transconductance	V _{DS} = 30 V, I _D = 5.0 A	--	10.7	--	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz	--	640	830	pF
C _{oss}	Output Capacitance		--	95	125	pF
C _{rss}	Reverse Transfer Capacitance		--	14	18	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	V _{DD} = 100 V, I _D = 10 A, R _G = 25 Ω (Note 4, 5)	--	13	35	ns
t _r	Turn-On Rise Time		--	150	310	ns
t _{d(off)}	Turn-Off Delay Time		--	50	110	ns
t _f	Turn-Off Fall Time		--	95	200	ns
Q _g	Total Gate Charge		V _{DS} = 160 V, I _D = 10 A, V _{GS} = 5 V (Note 4, 5)	--	13	17
Q _{gs}	Gate-Source Charge		--	2.4	--	nC
Q _{gd}	Gate-Drain Charge		--	6.1	--	nC

Drain-Source Diode Characteristics and Maximum Ratings

I _S	Maximum Continuous Drain-Source Diode Forward Current	--	--	10	A	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	40	A	
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 10 A	--	--	1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 10 A, (Note 4)	--	120	--	ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs	--	0.57	--	μC

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 2.7mH, I_{AS} = 10A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C
3. I_{SD} ≤ 10A, di/dt ≤ 300A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C
4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2%
5. Essentially independent of operating temperature

Typical Characteristics

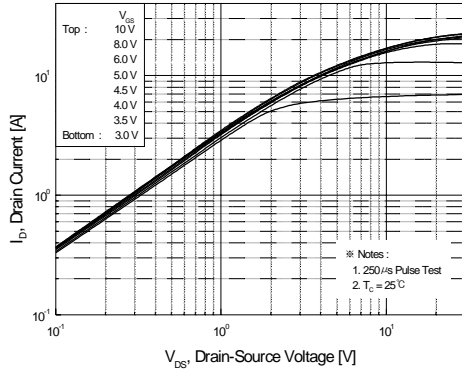


Figure 1. On-Region Characteristics

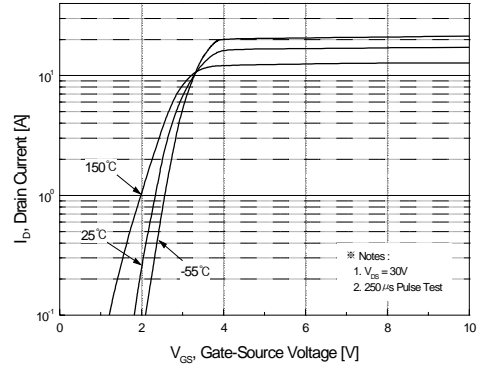


Figure 2. Transfer Characteristics

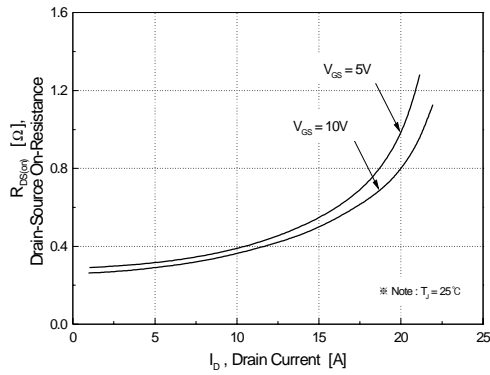


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

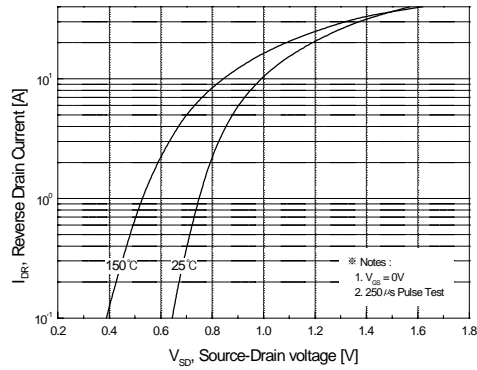


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

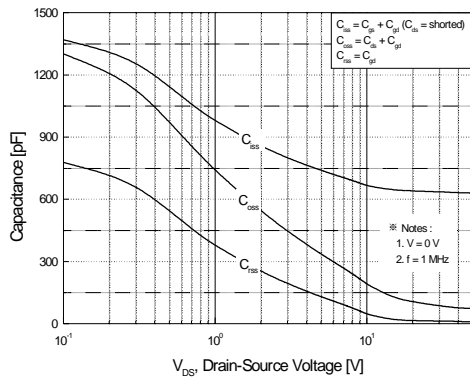


Figure 5. Capacitance Characteristics

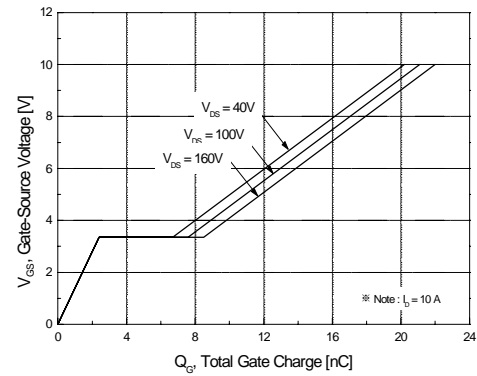


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

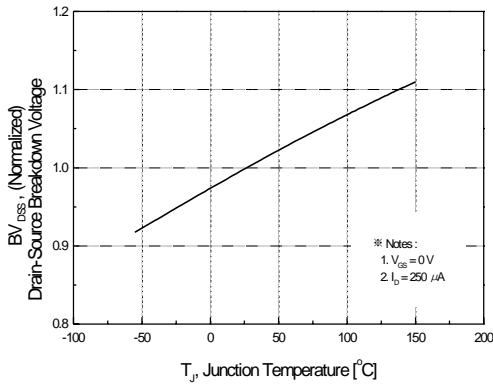


Figure 7. Breakdown Voltage Variation vs. Temperature

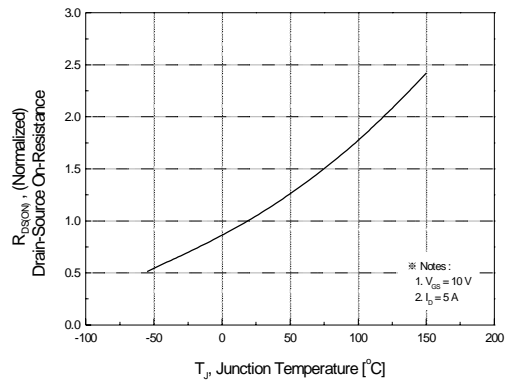


Figure 8. On-Resistance Variation vs. Temperature

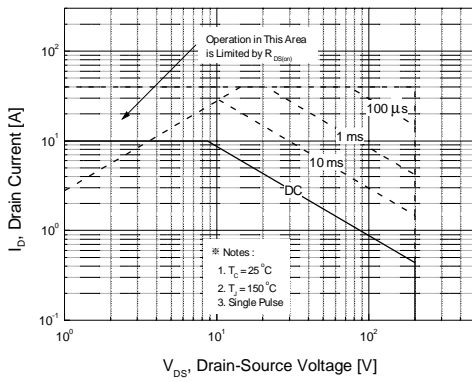


Figure 9. Maximum Safe Operating Area

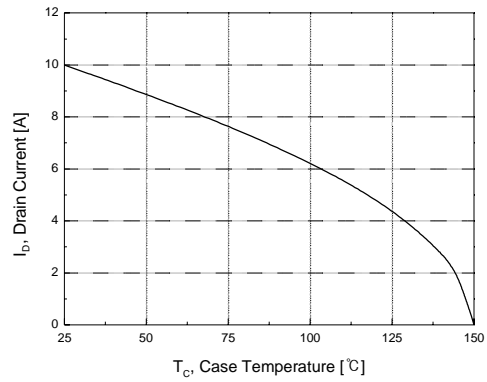


Figure 10. Maximum Drain Current vs. Case Temperature

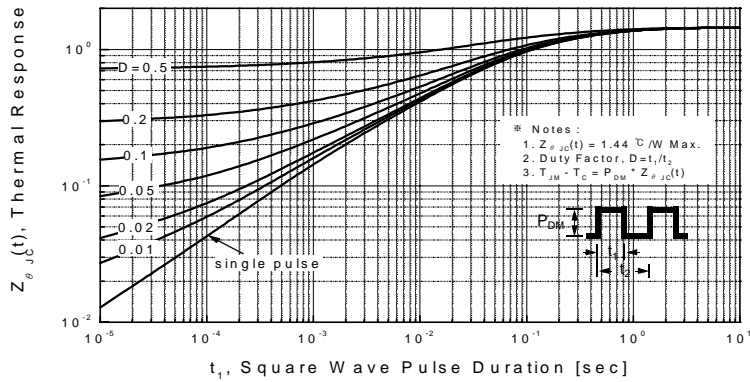
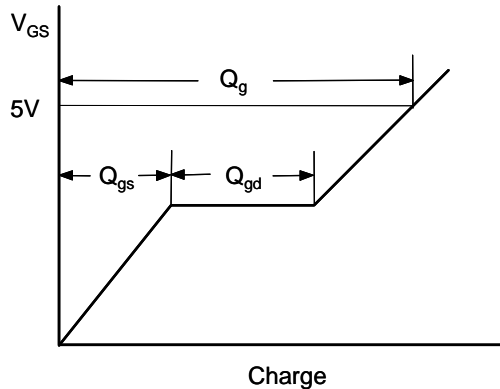
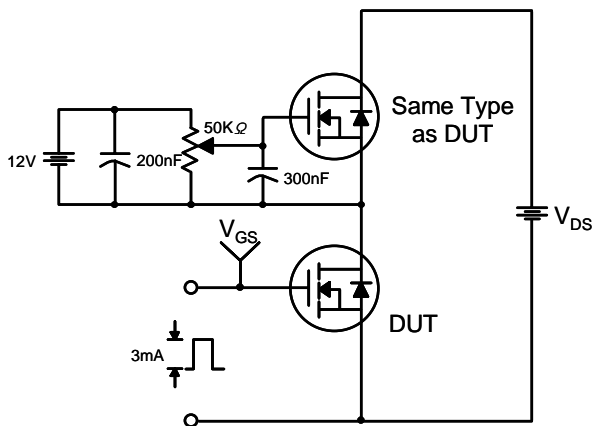
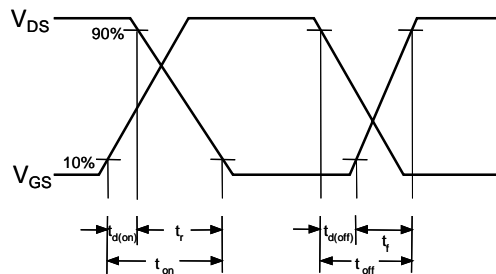
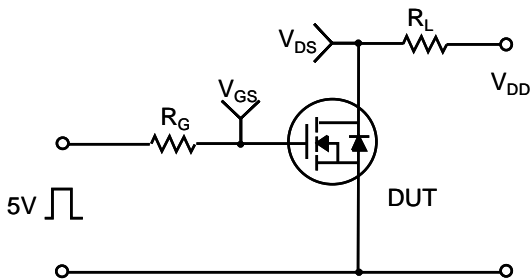


Figure 11. Transient Thermal Response Curve

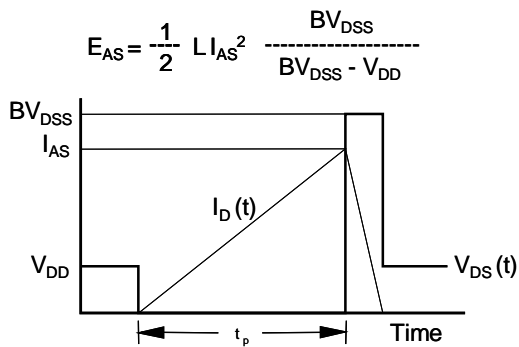
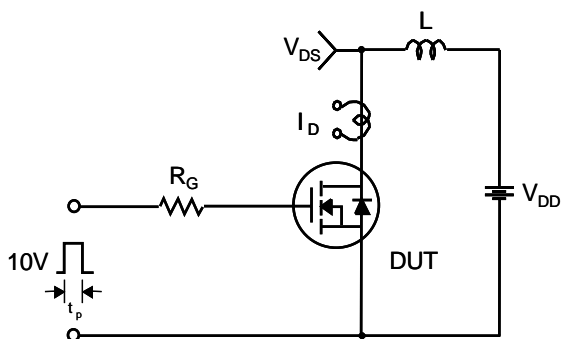
Gate Charge Test Circuit & Waveform



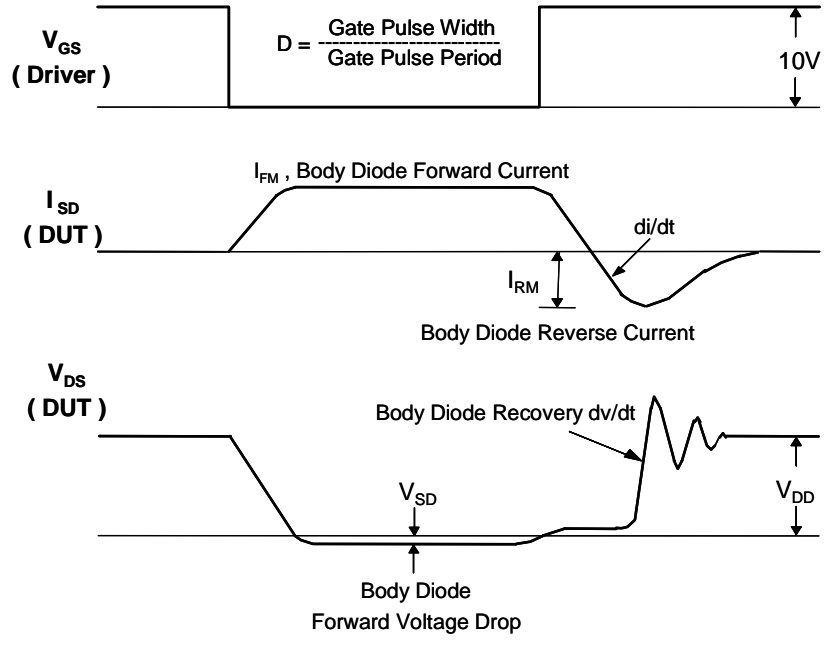
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



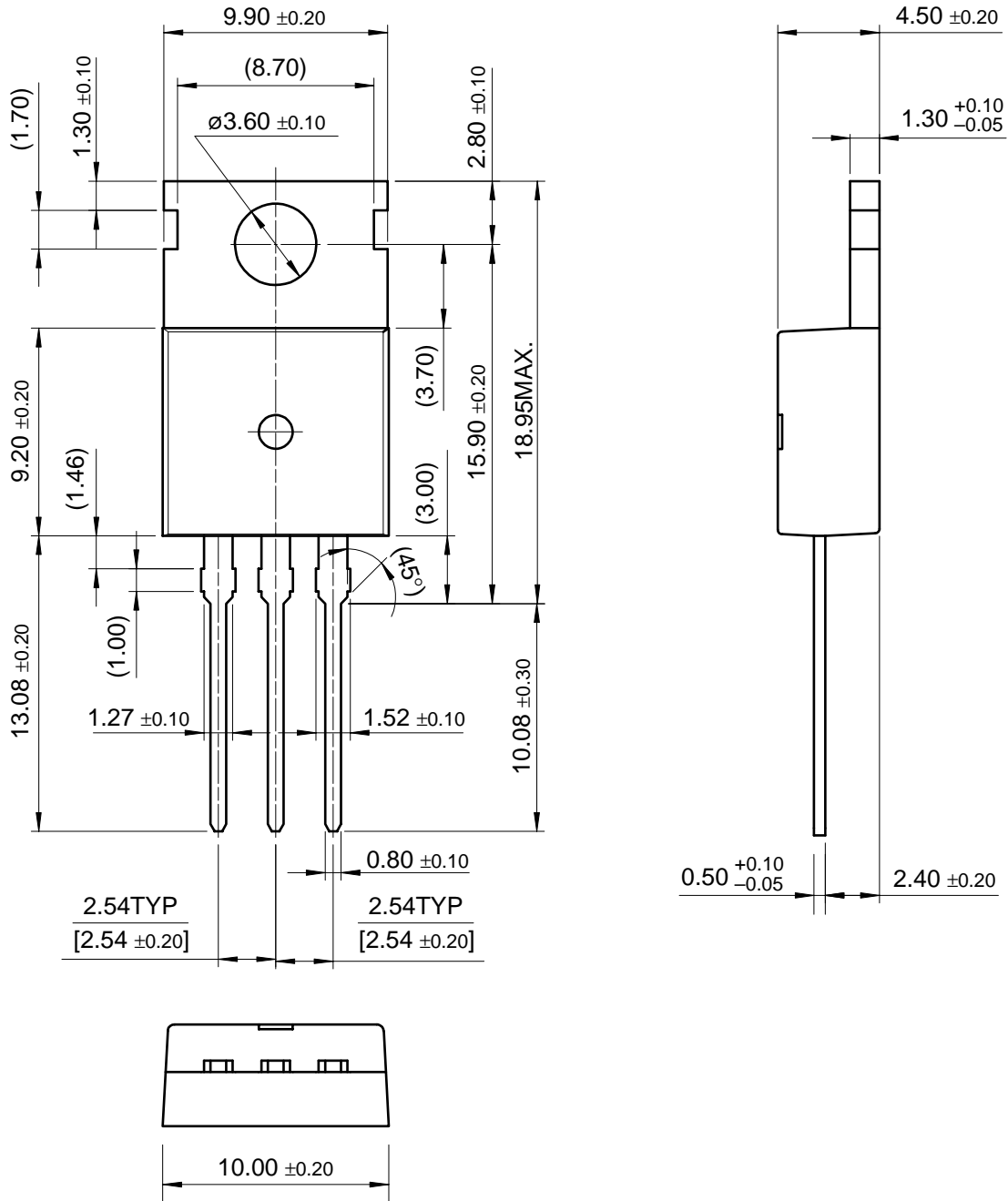
Peak Diode Recovery dv/dt Test Circuit & Waveforms



Package Dimensions

TO-220

FQP10N20L



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